

Search Notes

Application/Control No.

10/560,976

Examiner

TAN Q. NGUYEN

Applicant(s)/Patent under
Reexamination

WEIS ET AL.

Art Unit

3661

SEARCHED

Class	Subclass	Date	Examiner
701	1,2,200 211,207 117,118	7/23/2008	TN
340	992,905		
	995.13		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
701	1,2,117	8/3/2008	TN
340	992		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR